

Notice of References Cited

Application/Control No.

09/891,885

Applicant(s)/Patent Under

Reexamination

RAMSBET ET AL.

Examiner

Thomas J. Magee

Art Unit

2811

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,448,593 B1	09-2002	Masaaki Higashitani et al.	257/288
	B	US-5,378,649	01-1995	Heng S. Huang	437/52
	C	US-6,137,718	10-2000	Hans Reisinger	365/185.03
	D	US-5,953,601	09-1999	Ruey-Yun Shiue et al.	438/200
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Carlos H. Diaz, Thomas E. Kopley, and Paul J. Marcoux, "Building-In ESD/EOS Reliability for Sub-Half Micron CMOS Processes," IEEE Trans. on Electron Devices, Vol. 43, No. 6, (1996), pp.991 - 999.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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